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Reliability block diagrams (IEC 61078:2016)

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03.120.01	Kakovost na splošno	Quality in general
21.020	Značilnosti in načrtovanje strojev, aparatov, opreme	Characteristics and design of machines, apparatus, equipment

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(IEC 61078:2016)

Diagrammes de fiabilité
(IEC 61078:2016)

Zuverlässigkeitsblockdiagramme
(IEC 61078:2016)

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European Committee for Electrotechnical Standardization
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Europäisches Komitee für Elektrotechnische Normung

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European foreword

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The following dates are fixed:

• latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement	(dop)	2017-06-16
• latest date by which the national standards conflicting with the document have to be withdrawn	(dow)	2019-09-16

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In the official version, for Bibliography, the following notes have to be added for the standards indicated:

IEC 61025	NOTE	Harmonized as EN 61025.
IEC 61165	NOTE	Harmonized as EN 61165.
IEC 62551	NOTE	Harmonized as EN 62551.
IEC 60812	NOTE	Harmonized as EN 60812.
IEC 61508:2010 Series	NOTE	Harmonized as EN 61508:2010 Series.
IEC 61511:2016 Series	NOTE	Harmonized as EN 61511:2016 Series.
ISO/TR 12489	NOTE	Harmonized as CEN ISO/TR 12489.

Annex ZA
(normative)

Normative references to international publications with their corresponding European publications

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 When an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cenelec.eu

Publication	Year	Title	EN/HD	Year
IEC 60050-192	-	International Electrotechnical Vocabulary - Part 192: Dependability	-	-
IEC 61703	-	Mathematical expressions for reliability, availability, maintainability and maintenance support terms	EN 61703	-

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Reliability block diagrams

Diagrammes de fiabilité

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

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RELIABILITY BLOCK DIAGRAMS

FOREWORD

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International Standard IEC 61078 has been prepared by IEC technical committee 56: Dependability.

This third edition cancels and replaces the second edition published in 2006. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

a) the structure of the document has been entirely reconsidered, the title modified and the content extended and improved to provide more information about availability, reliability and failure frequency calculations;
b) Clause 3 has been extended and clauses have been introduced to describe the electrical analogy, the "non-coherent" RBDs and the "dynamic" RBDs;
c) Annex B about Boolean algebra methods has been extended;
d) Annex C (Calculations of time dependent probabilities), Annex D (Importance factors), Annex E (RBD driven Petri net models) and Annex F (Numerical examples and curves) have been introduced.

The text of this standard is based on the following documents:

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Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

The committee has decided that the contents of this publication will remain unchanged until the stability date indicated on the IEC web site under "http://webstore.iec.ch" in the data related to the specific publication. At this date, the publication will be

- reconfirmed,
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- amended.